

Notice of References Cited	Application/Control No. 10/782,214	Applicant(s)/Patent Under Reexamination KITAGAWA, HITOSHI	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0135863	09-2002	Fukshima et al.	359/298
	B	US-6,064,506	05-2000	Koops, Hans	359/237
	C	US-2001/0012149	08-2001	LIN et al.	359/344
	D	US-2001/0026659	10-2001	Sekine et al.	385/40
	E	US-2002/0041425	04-2002	Baba et al.	359/322
	F	US-6,433,919	08-2002	Chowdhury et al.	359/332
	G	US-2002/0110306	08-2002	Hamada, Hidenobu	385/11
	H	US-2002/0109134	08-2002	Iwasaki et al.	257/13
	I	US-2002/0135863	09-2002	Fukshima et al.	359/298
	J	US-2002/0146196	10-2002	Shirane et al.	385/16
	K	US-2003/0039446	02-2003	Hutchinson et al.	385/39
	L	US-2003/0053352	03-2003	Hamada, Hidenobu	365/200
	M	US-6,542,654	04-2003	Miller et al.	385/16

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0128949	07-2003	Kitagawa et al.	385/129
	B	US-2003/0142385	07-2003	Kittaka et al.	359/279
	C	US-2003/0202764	10-2003	Lee et al.	385/129
	D	US-2004/0001665	01-2004	Zoorob, Majd	385/16
	E	US-2004/0021193	02-2004	Nathan et al.	257/499
	F	US-2004/0069948	04-2004	Feisst et al.	250/343
	G	US-6,735,368	05-2004	Parker et al.	385/122
	H	US-2004/0150873	08-2004	Pearsall, Thomas P.	359/321
	I	US-2004/0184752	09-2004	Aoki et al.	385/123
	J	US-6,813,399	11-2004	Hamada, Hidenobu	385/11
	K	US-6,822,784	11-2004	Fukshima et al.	359/298
	L	US-2005/0002605	01-2005	Sakai et al.	385/027
	M	US-2005/0030611	02-2005	Fukshima et al.	359/321

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0084213	04-2005	Hamann et al.	385/040
	B	US-6,888,994	05-2005	Baumberg et al.	385/129
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
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